



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Advanced Component Testing

3279 Veterans Memorial Hwy.
Ronkonkoma, NY 11779

Fulfills the requirements of

ISO/IEC 17025:2017

In the field of

TESTING

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

A handwritten signature in black ink, appearing to read 'R. Douglas Leonard Jr.', is positioned above a horizontal line.

R. Douglas Leonard Jr., VP, PILR SBU

Expiry Date: 13 February 2023
Certificate Number: AT-1757



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

Advanced Component Testing

3279 Veterans Memorial Hwy.
Ronkonkoma, NY 11779

Mike Zambito Phone: 631 676 6390
mzambito@actestlab.com www.actestlab.com

TESTING

Valid to: **February 13, 2023**

Certificate Number: **AT-1757**

Destructive

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
External Visual Inspection (EVI)	Internal Procedure IDEA-STD-1010B; AS6081 AS6171/2 (Method A & B)	Electrical, Electronic and Electromechanical (EEE) Components	Dino-Lite Camera
Remarking and Resurfacing Test	MIL-STD-202G, Method 215K IDEA-STD-1010B; AS6081 Internal Procedure AS6171/2 (Method C & D)	Electrical, Electronic and Electromechanical (EEE) Components	Mark-Scrape test Chemical Solution Dynasolve Digital Thermometer
Packaging Configuration and Dimensions	MIL-STD-883 Method 2016 Internal Procedure; AS6081 AS6171/2 (Method E)	Electrical, Electronic and Electromechanical (EEE) Components	Calipers Device to print Package Dimensions
SEM Surface Texture Analysis	Internal Procedure; AS 6081 AS 6171/2 (Method F)	Electrical, Electronic and Electromechanical (EEE) Components	SEM Scanning Electron Microscope
X-Ray Fluorescence (XRF) <i>(only with samples with area >7 mm²)</i>	Internal Procedure; AS6081 AS6171/3	Electrical, Electronic and Electromechanical (EEE) Components	Niton XL3t / test slug
Radiographic Inspection	Internal Procedure; AS6081 AS6171/5	Electrical, Electronic and Electromechanical (EEE) Components	Glenbrook Jewel Box 70T
Delid/Decapsulation Physical Analysis (DDPA)	IDEA-STD-1010B; AS6081 Internal Procedure AS6171/4	Electrical, Electronic and Electromechanical (EEE) Components	Nisene Jet-Etch Decapsulator, Microscope
Solderability	MIL-STD-883 Method 2003.9 Internal Procedure	Electrical, Electronic and Electromechanical (EEE) Components	RPS Steam Ager Solder Pots Digital Thermometer

Non-Destructive

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Electrical Test (ET) Passive Devices (Resistance, Capacitance, Inductance)	MIL-STD-202G, Method 303A AS6171/7	Electrical, Electronic and Electromechanical (EEE) Components	LCR HP 4275A
Electrical Test (ET) Active Devices (Group A Electrical)	MIL-STD-883 AS6171/7	Electrical, Electronic and Electromechanical (EEE) Components	ATE and various Electronic Lab Equipment Temperature Chamber

Note:

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AT-1757.



R. Douglas Leonard Jr., VP, PILR SBU

